



GOVERNMENT OF INDIA
ELECTRONICS REGIONAL TEST LABORATORY (WEST)
MINISTRY OF ELECTRONICS & INFORMATION TECHNOLOGY,
STQC DIRECTORATE.

COVER SHEET

TESTING REPORT

REPORT NO.:ERTL(W) 2018 SAF 36

DATE OF ISSUE : 28 SEP 2018

PAGE 01 OF REPORT

TITLE: TESTING OF LAB GROWN DIAMOND DETECTOR

1.1 Service Request No.and Date : 20180391 , 23-AUG-18

1.2 Name and Address of Customer: M/s. **AROTEK SCIENTIFIC INSTRUMENTS PVT.LTD**
SHOP NO.-8, BLDG. NO-5
AMRUT AANGAN, PHASE II, PARIK NAGAR, KALWA (WEST)
THANE-400605
THANE

1.3 Report in the Name of: M/s. **AROTEK SCIENTIFIC INSTRUMENTS PVT.LTD**
SHOP NO.-8, BLDG. NO-5
AMRUT AANGAN, PHASE II, PARIK NAGAR, KALWA (WEST)
THANE-400605
THANE

Report Released By:

J L N MURTY / V R CHAVAN
Customer Service Cell





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REPORT NO. : ERTL (W)/ 2018SAF36

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TITLE: TESTING OF LAB GROWN DIAMOND DETECTOR

DATE OF ISSUE
28-Sept-2018

1.0 SCOPE:

1.1	Service request no and Date	As per cover sheet		
1.2	Name and address of Customer:	As per cover sheet		
1.3	Description & Identification of Test item(s)	Nomenclature :	LAB GROWN DIAMOND DETECTOR *	
		Manufacturer :	AROTEK SCIENTIFIC INSTRUMENTS PVT Ltd *	
		Model/Type	Qchk Adc *	
		Sl. No. :	QCHKADC 00001 *	
		Quantity:	01	
1.4	Item(s) condition on receipt: OK	J/C Received	Sample Received	Test Completed
		24-08-2018	24-08-2018	20/09/2018
1.5	Testing performed at :	At ERTL (W), Mumbai.		
1.6	Laboratory Ambient :	Temperature: (25 ± 3) °C ; Humidity: (45 To 75) % RH		
1.7	Test Specification / Test Procedure used.	IEC 61010-1: (Edition 3.1) : 2017		
1.8	Major Equipments used and Traceability Details:			
Sl. No.	Equipment Used	Uncertainty (Best Case)	Calibration Report Ref.	Valid up to
1	Electrical Safety Analyzer	± 1.5 %	2017S&C565	07/12/2018
2	4½ Digital Multi-meter	± 0.12 %	2018S&C124	28/02/2019
3	Digital Power Meter	± 0.04 %	2017S&C532	10/11/2018
4	Hybride Temperature Recorder	±0.3 °C	2017TNP214	02/11/2018

* As marked on test item.



QSF 5.10.09 dated 01/01/2014

TRF No. IEC61010_1L



TEST REPORT IEC 61010-1 Safety requirements for electrical equipment for measurement, control, and laboratory use Part 1: General requirements	
Report Number.....	: ERTL(W)/2018SAF36
Date of issue.....	: 28-Sept-2018
Total number of pages	: 95
Name of Testing Laboratory preparing the Report	: ELECTRONICS REGIONAL TEST LABORATORY (WEST)
Applicant's name	: AROTEK SCIENTIFIC INSTRUMENTS PVT.LTD.
Address.....	: Shop No. 8, Amrut Aangan, Phase-II, Building No. 5, Parsik Nagar, Kalwa west, Thane-400605.
Test specification:	
Standard	: IEC 61010-1:2010, AMD1:2016 (Edition 3.1)
Test procedure	: ERTL(W)/SAF/PROCEDURE
Non-standard test method	: N/A
Test Report Form No.	: IEC61010_1L
Test Report Form(s) Originator	: VDE Testing and Certification Institute
Master TRF	: 2017-10-20
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General disclaimer:	
The test results presented in this report relate only to the object tested. This report shall not be reproduced, except in full, without the written approval of the Issuing CB Testing Laboratory. The authenticity of this Test Report and its contents can be verified by contacting the NCB, responsible for this Test Report.	



Test item description	LAB GROWN DIAMOND DETECTOR	
Trade Mark	Nil	
Manufacturer	AROTEK SCIENTIFIC INSTRUMENTS PVT. LTD	
Model/Type reference	Qchk Adc	
Ratings	230/110 VAC, 0.5/0.8 A, 50/60 Hz,	
Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):		
<input checked="" type="checkbox"/> Testing Laboratory:		
Testing location/ address	ELECTRONICS REGIONAL TEST LABORATORY (WEST) Opp SEEPZ, Plot F7&8, MIDC Marol Area, Andheri (E), Mumbai-93	
Tested by (name, function, signature)	Rahul Jagtap, Scientist 'B'	
Checked by (name, function, signature)	Lata Gholap Scientist 'C'	
Approved by (name, function, signature)....	Vinod K Dhar, Scientist 'E'	